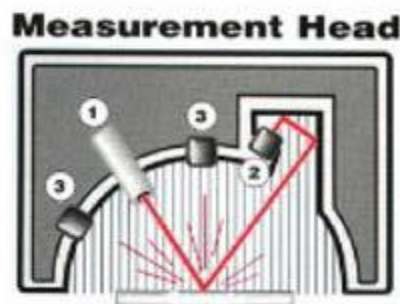


We offer roughness measuring of optical surfaces

We offer contract measuring on hand roughness measuring device μ Scan from SCHMITT Industries, Inc. company.

- μ Scan is used for quick non-contact measuring of:
 - roughness of optical surfaces.
 - manufacturing control of work surface quality.
- Advantages of μ Scan device:
 - hand-held portable device.
 - the value of middle quadratic deviation of surface roughness R_q , middle nominal deviations of roughness surface R_a , reflectivity and space scattering function BRDF are directly displayed.
 - interconnection with PC for result stacking and statistical measuring evaluation.
 - non-destructive and fully automatic measurement.
 - adjustable for plane and curved surfaces.
 - interchangeable measuring heads.
- Device measures values of middle quadratic deviations of surface roughness R_q , reflectivity and space scattering function BRDF on wavelengths 670 nm or 1300 nm.
- Measuring ranges:
 - $R_a, R_q: 1\text{\AA} - 1100\text{\AA}$.
 - Reflectivity: 0,1 – 100,0%.
 - BRDF: $10^{-6}\text{ sr}^{-1} - 1\text{ sr}^{-1}$.



 **μ Scan®**

Measuring the optical surface roughness and its scattering properties

We offer contract measuring on peak light scatter instrument and roughness measuring instrument CASI from SCHMITT Industries, Inc.

- CASI (*Complete Angle Scatter Instrument*) uses laser beam for contactless measuring:
 - optical surface roughness.
 - material pollution.
 - defects and regular structures.
 - complete scattered radiation field from materials.
- Measuring is possible on a wide range of materials:
 - accurately wrought optical surfaces.
 - all diffuse materials.
 - semiconductor wafers.
 - mechanical components.
- The smallest measurable mid quadratic value RMS (R_q) of the surface roughness is <1 nm. Therefore it outreaches by its accuracy measuring systems based on mechanical scanning of the surface.
- Instrument measures all important parameters of the scattered radiation on wavelengths 325 nm and 633 nm.
- Scattered light field from the material is being measured in through field, as well as in reflected field in the interval -90° – 90° from the surface normal.

